

Fig. 1

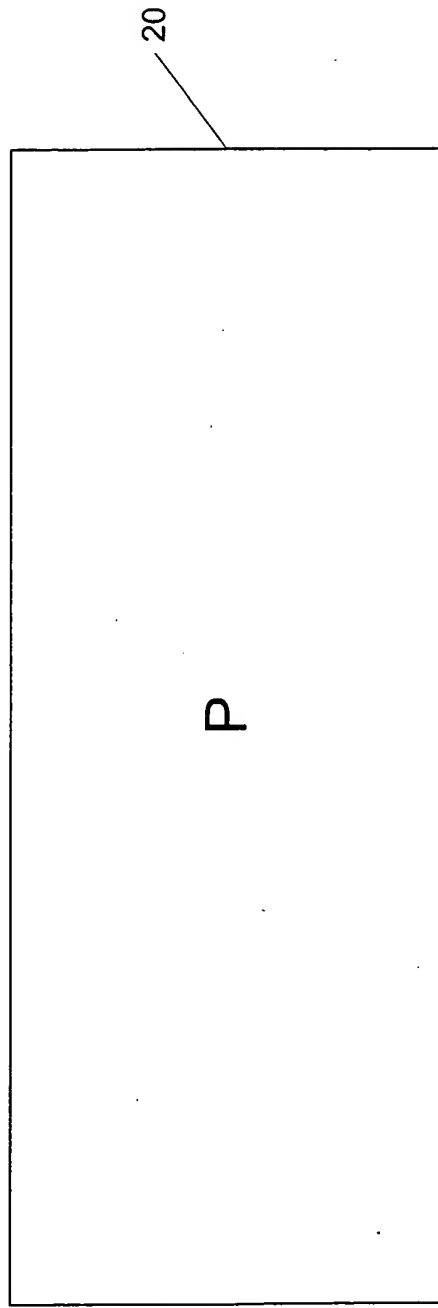


Fig. 2a

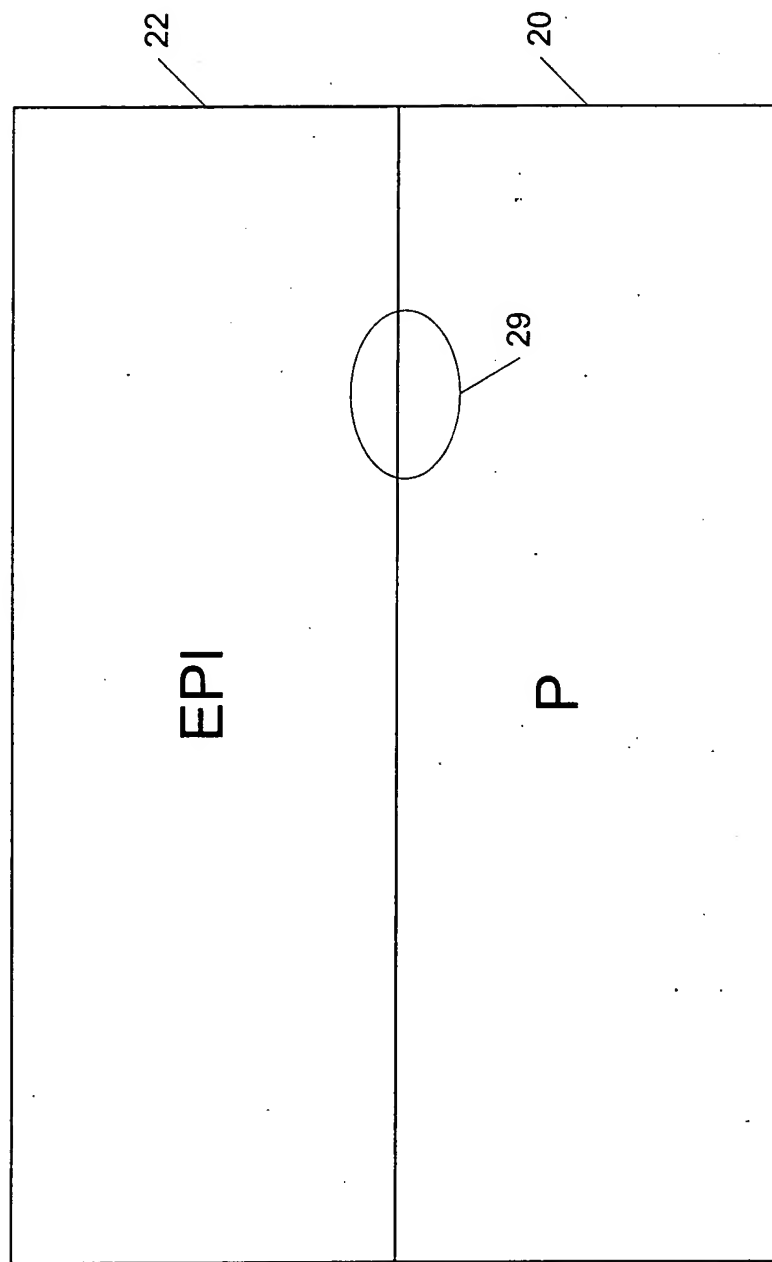


Fig. 2b

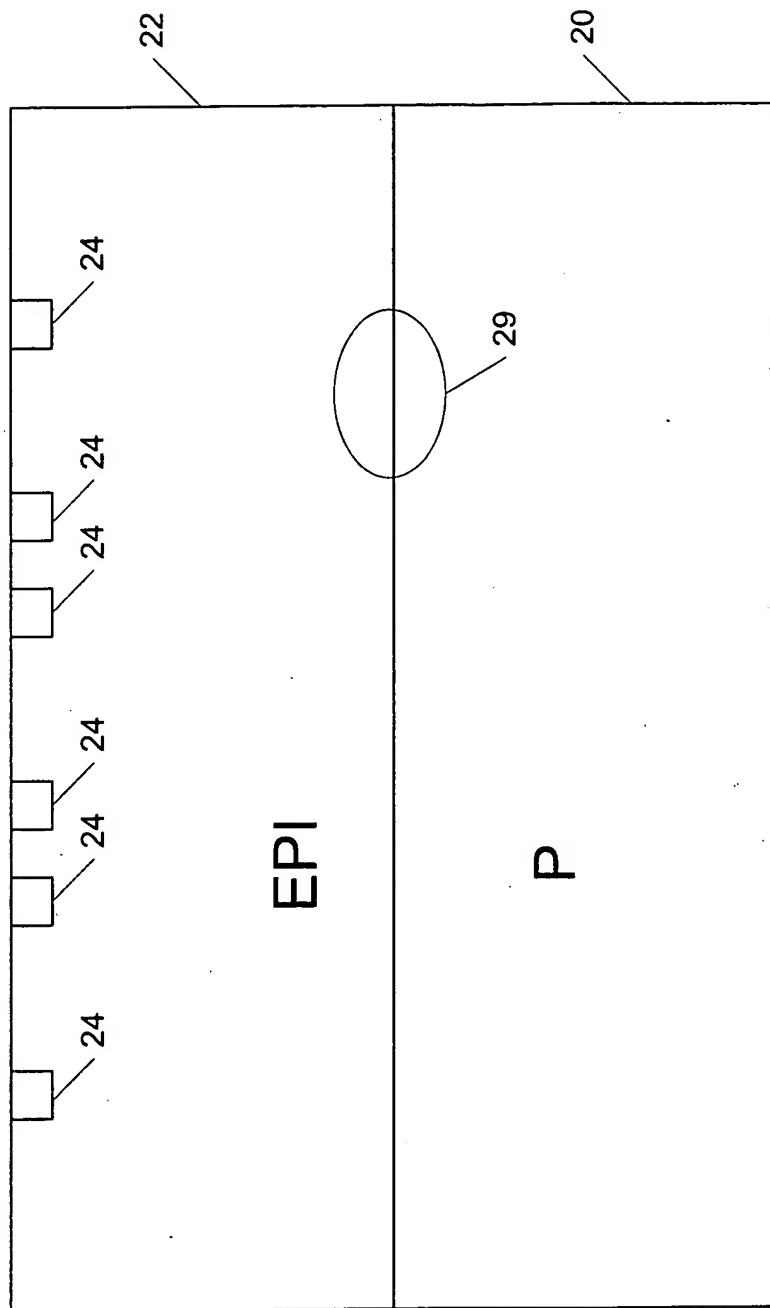


Fig. 2c

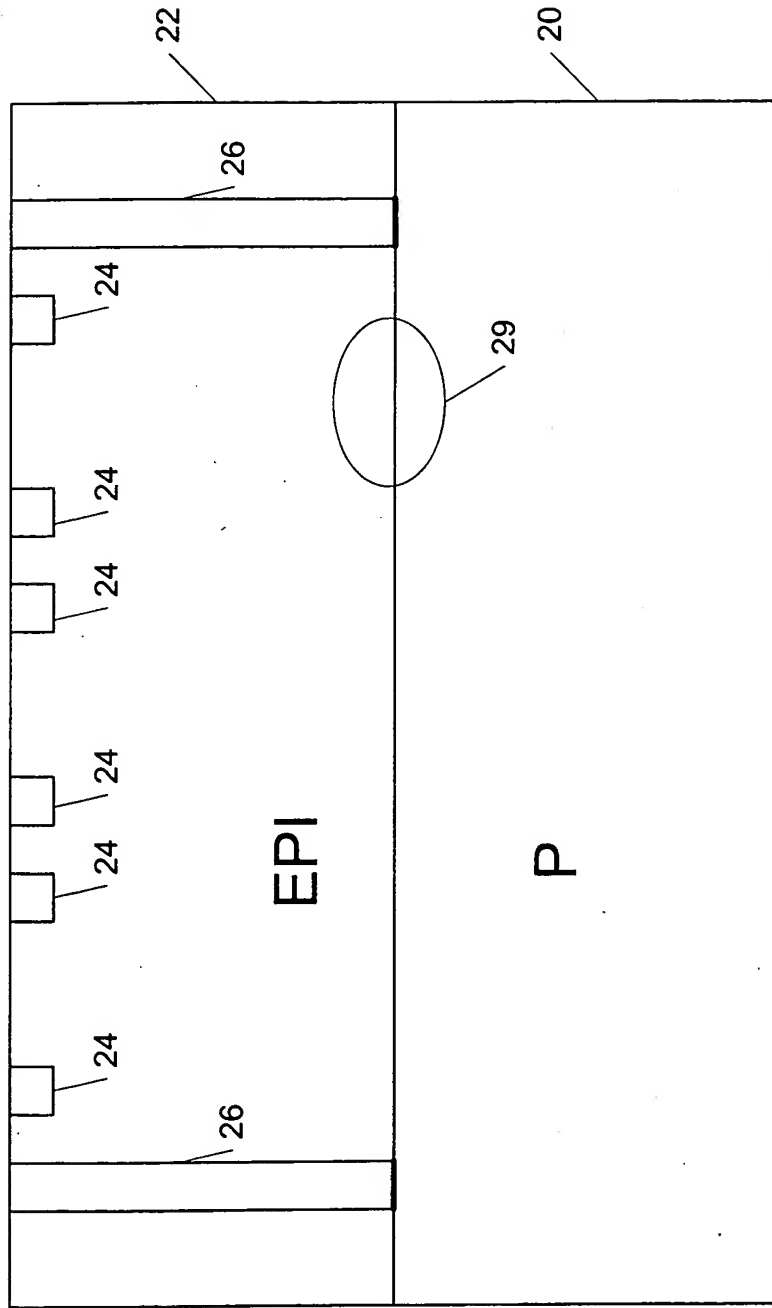


Fig. 2d

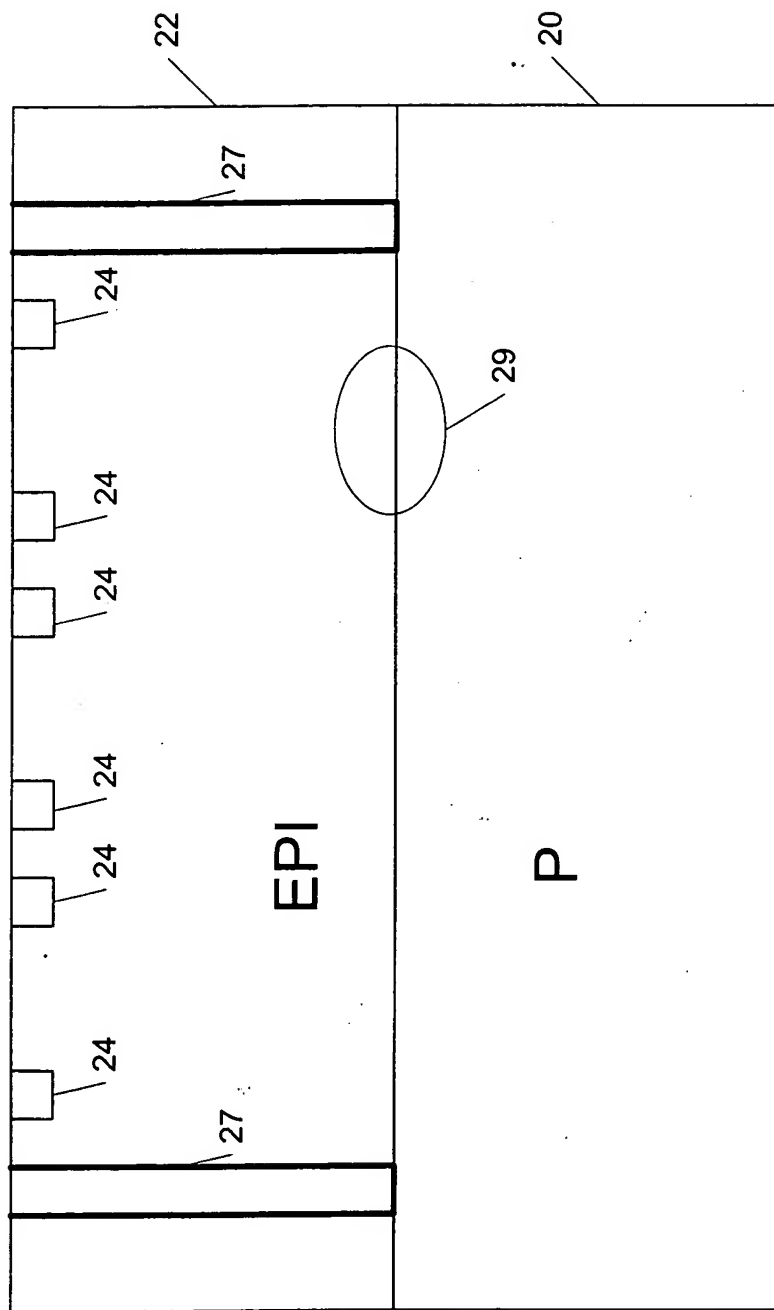


Fig. 2e

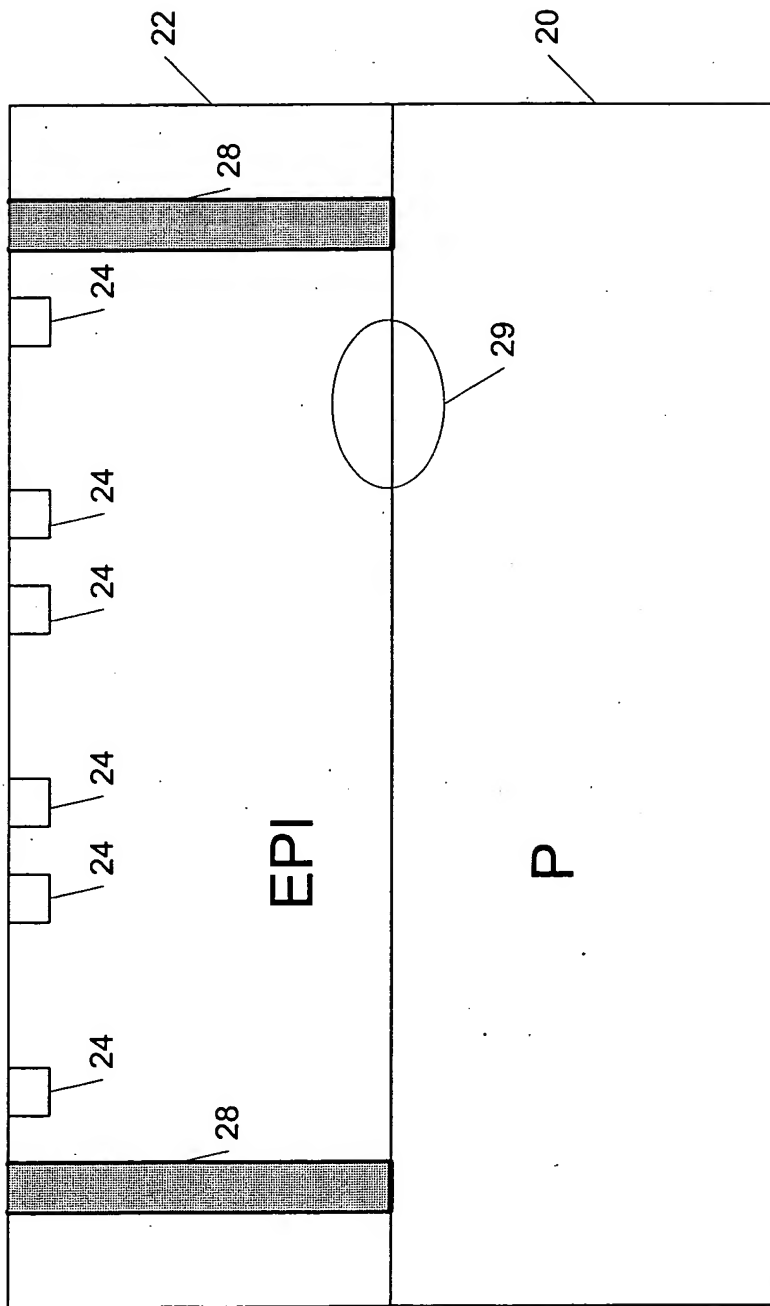


Fig. 2f

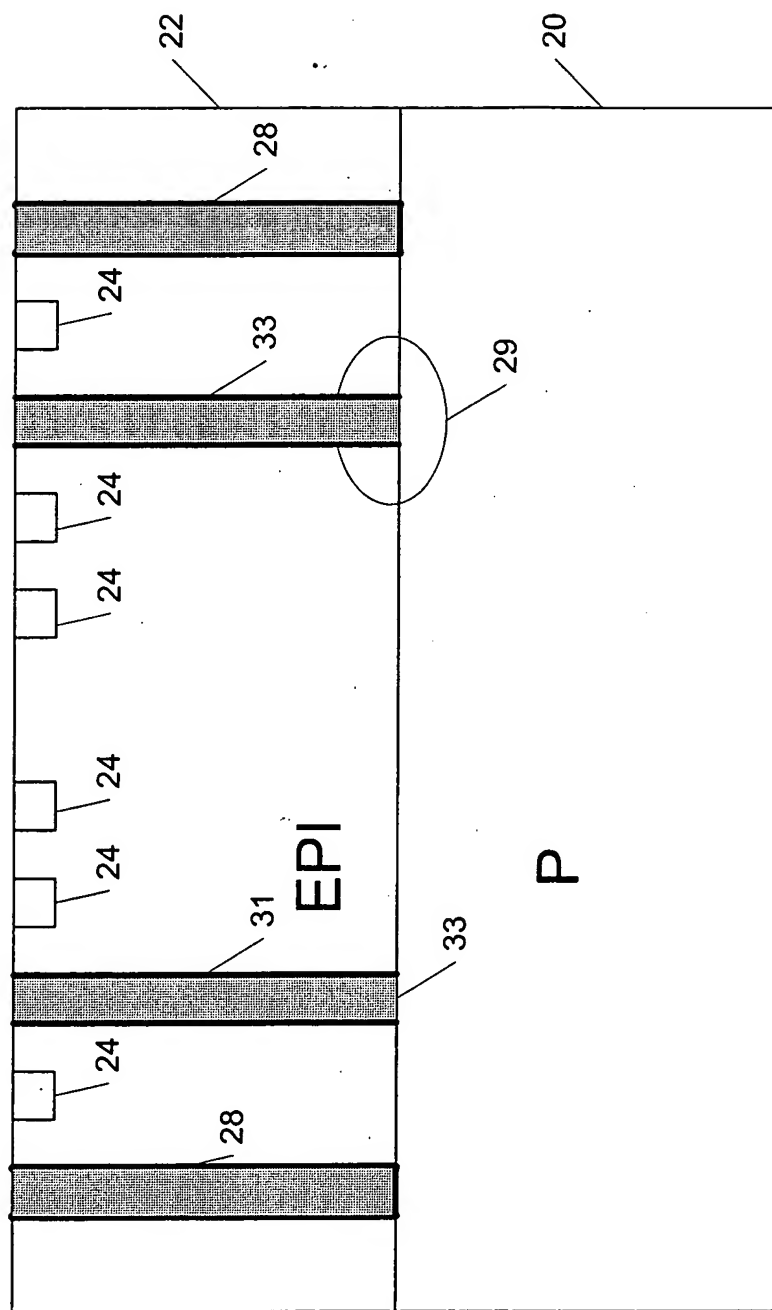


Fig. 29

10034279-122801

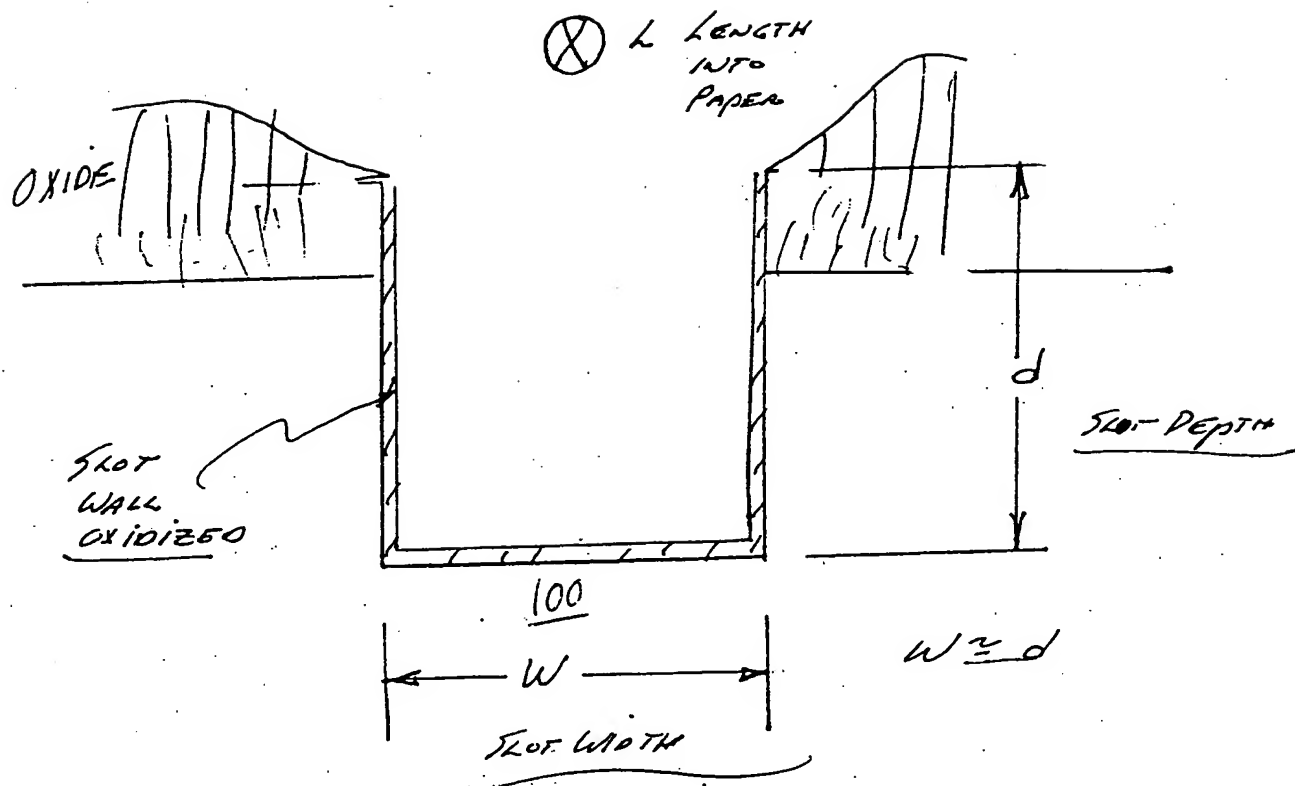


Fig. 3

10034279-122801

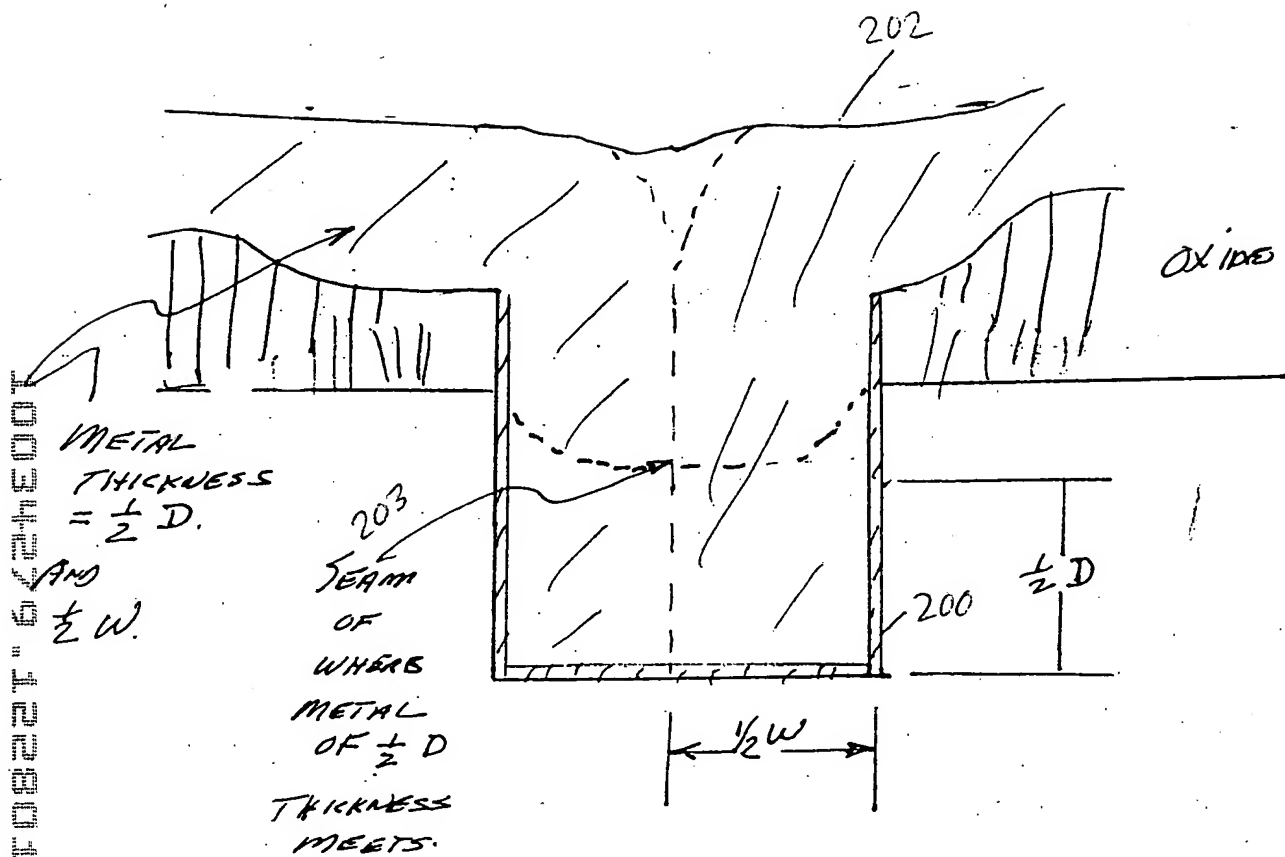


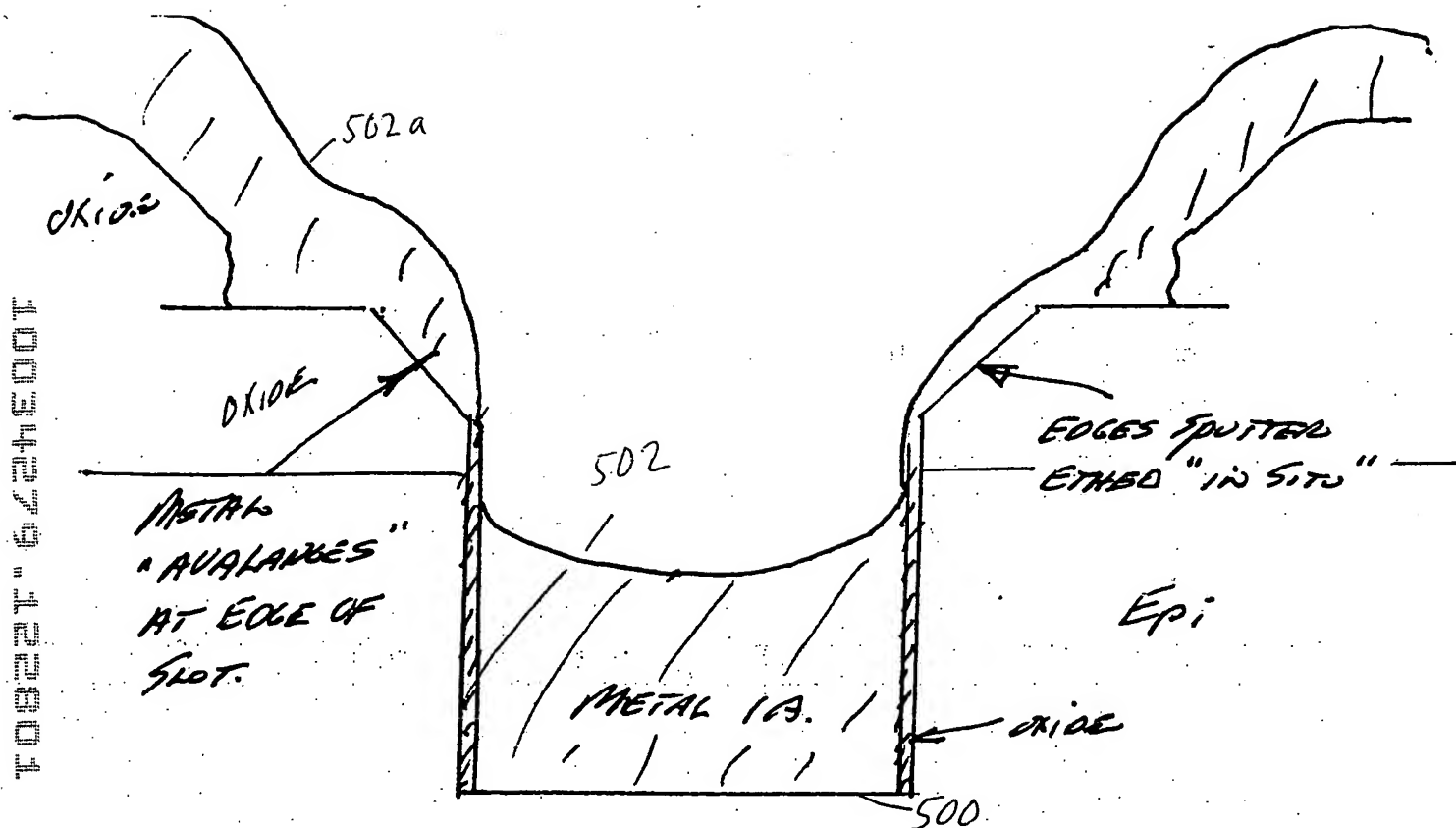
Fig. 4

Hand-drawn schematic of a cross-section of a device. The diagram shows a central rectangular region labeled "OXIDE" with a hatched top section. This central region is flanked by two vertical lines. Below the central region, there are three horizontal segments labeled "5um SLOT", "3um SPACE", and "5um SLOT". To the left of the first slot is a vertical line labeled "302". To the right of the last slot is a vertical line labeled "304". The height of the central region is labeled "5um" on the right side.

DOUBLE SLOT FOR
DOUBLE WIDTH OF METAL.
3/4" SPACE BETWEEN SLOTS

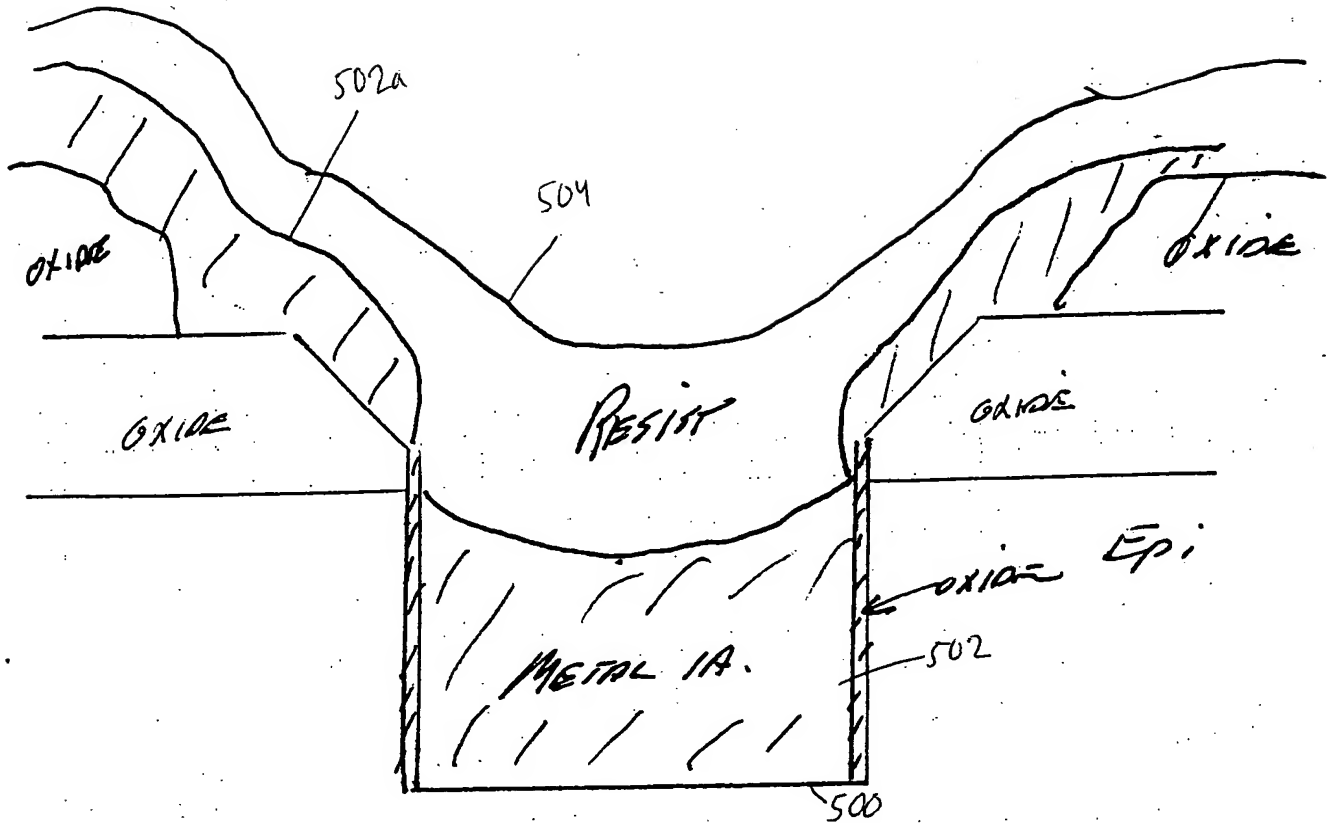
Fig. 4a

10034279-122801



Prior TO METAL 1A BEING
SPUTTERED, THE EDGES OF THE OXIDES
ARE SPUTTERED ETCHED "IN SITU" &
1A DEPOSITED

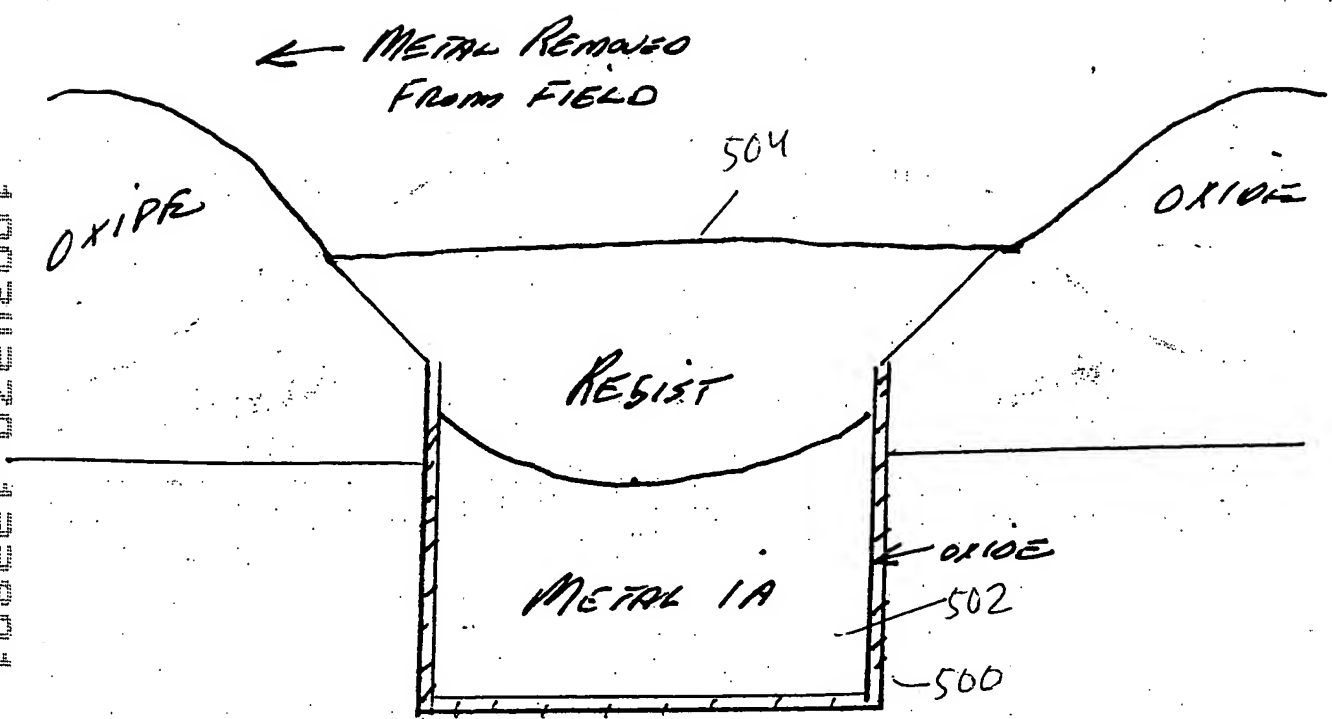
Fig. 5



RESIST COATING - THICK IN THE
SLOTS

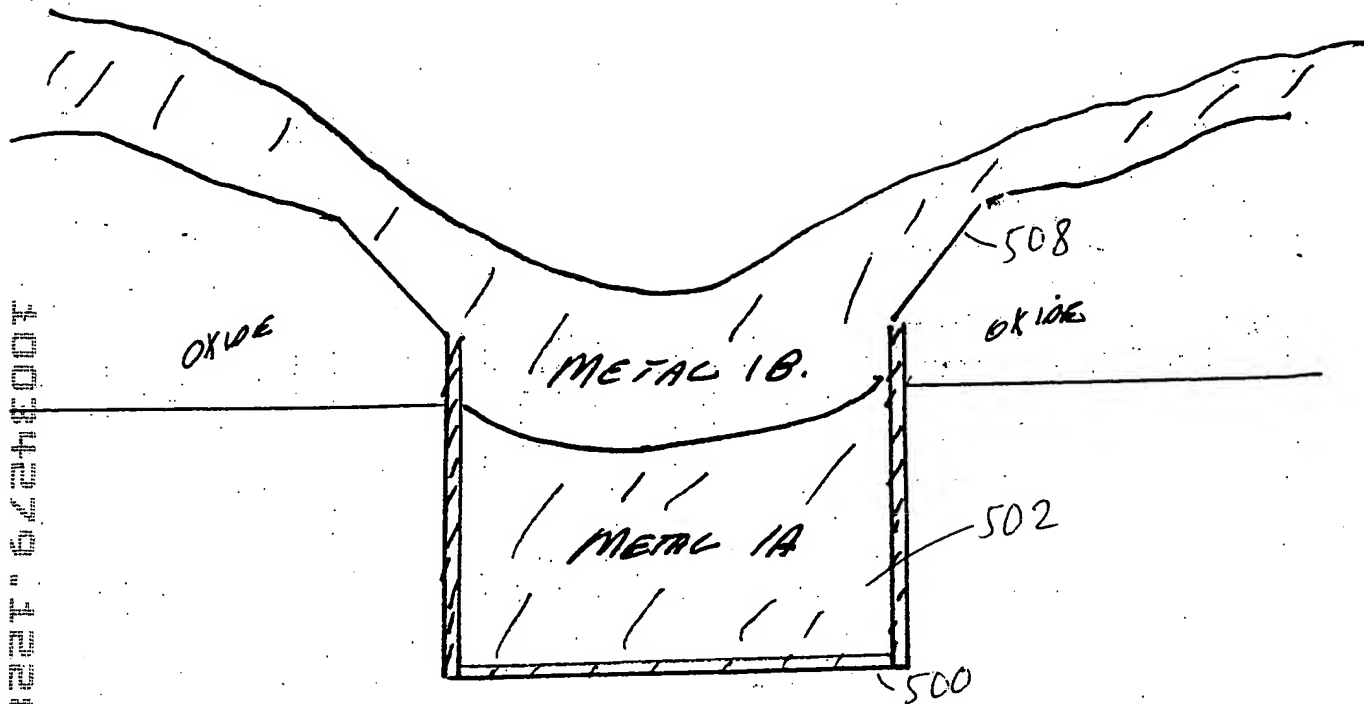
Fig. 6

10034279-122801
FOOT SHEET



RESIST PLANNED ETCHED.
LEAVING RESIST IN SLOTS
FIELD METAL ETCHED OFF.

Fig. 7



RESIST STRIPPED & SECOND
METAL 1B SPUTTER DEPOSITED

Fig. 8

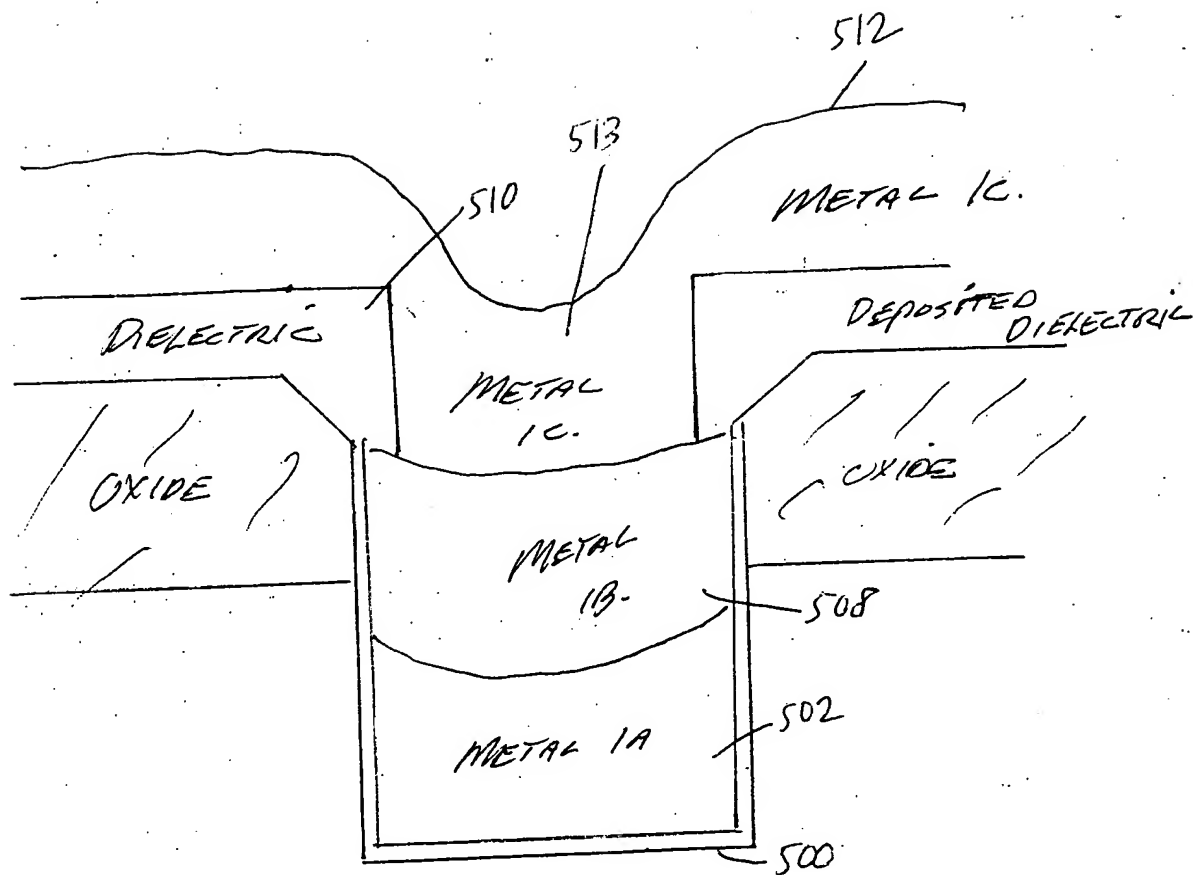


Fig. 9

10034279.12804

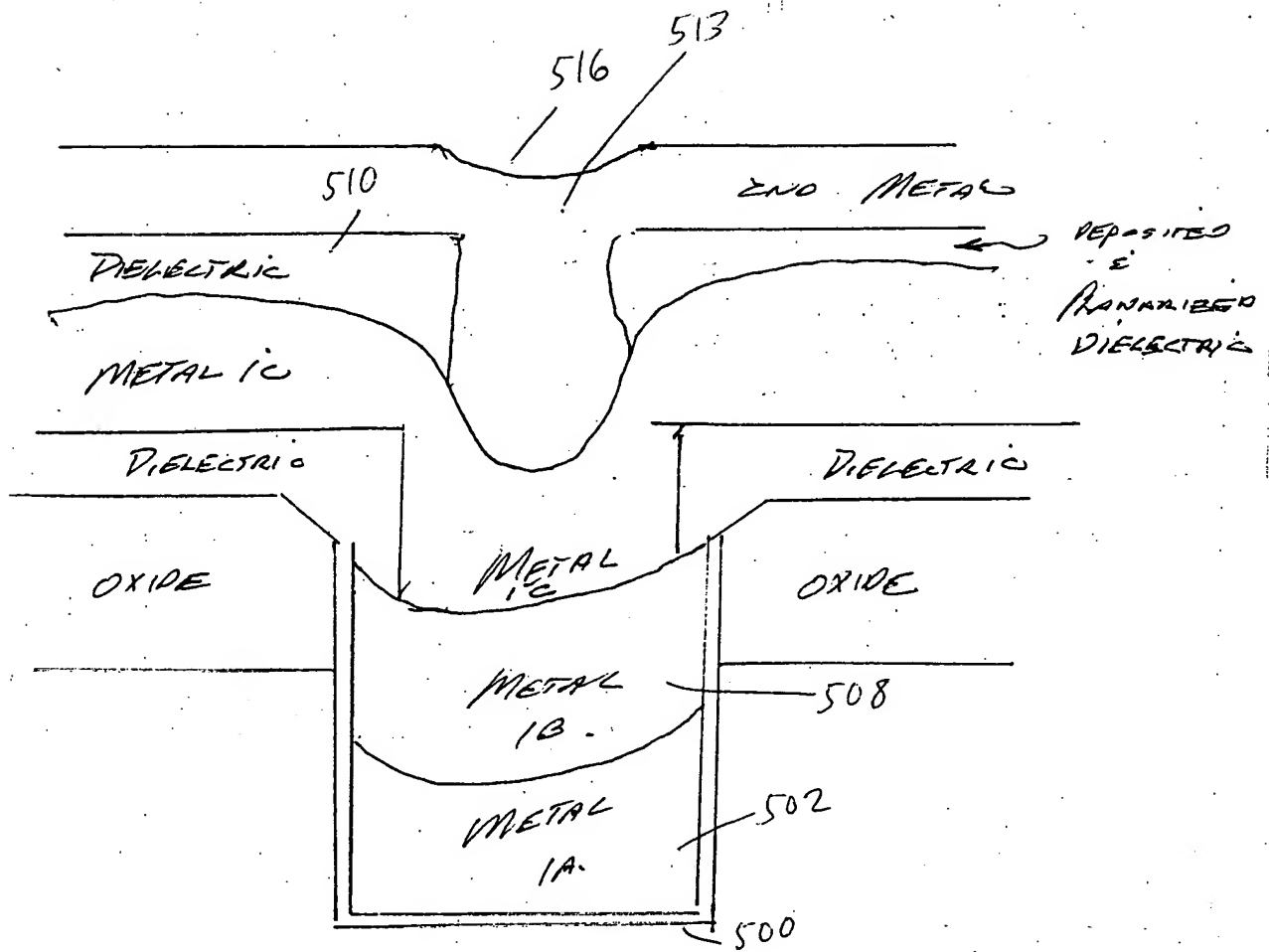
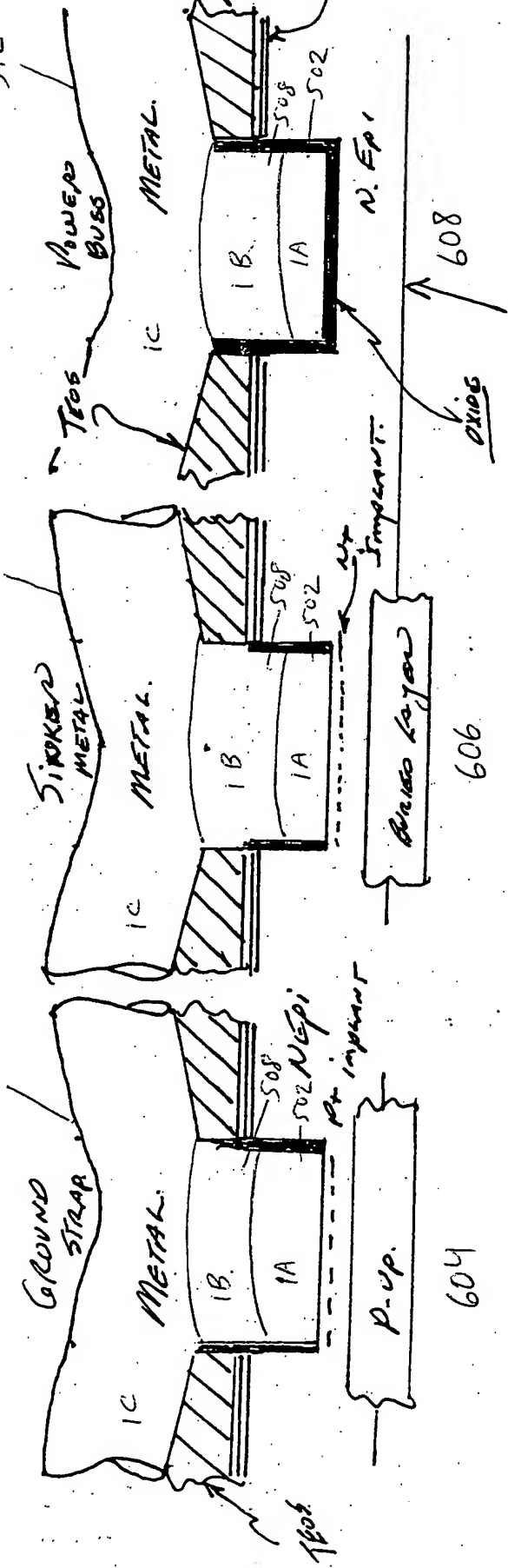


Fig. 10



Ground Strap

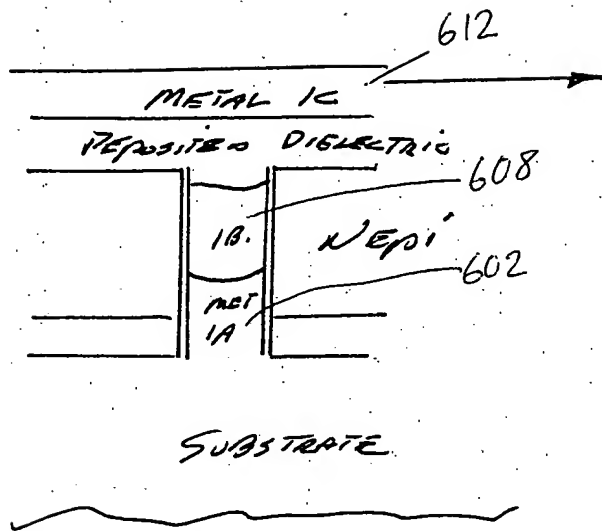
Drain/Buried
layer / Not Impurant

Power Buses

Ground Strap / Power Buses / Drain Metal Sinkers

Thin outer layer of DIELECTRIC
FOLLOWED BY 9000 Å TEOS - POLISH -
THAT MASS - METAL.
METAL 15-20 nm deposited

Fig. 11 Power Metal.



METAL 1C
 CONNECTS AN ISOLATED
 ISLAND TO ADJACENT
 ISOLATED EPI ISLANDS
 AND CROSSES OVER THE
 ISOLATION GROUND
 STRAP BY NOT OPENING
 A VIA IN THIS PORTION
 TO ALLOW IC TO BE
 ISOLATED FROM GROUND.

Fig. 12